

# ISO/TS 11353:2026-01 (E)

## Nanotechnologies - A test method for detection of nano-object(s) release from mask media

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Contents	Page
Foreword .....	iv
Introduction .....	v
1 Scope .....	1
2 Normative references .....	1
3 Terms and definitions .....	1
4 Abbreviation terms .....	4
5 Classification .....	4
6 Test requirements .....	5
6.1 Qualification of nano-objects in the mask media .....	5
6.2 Test rig components .....	5
7 Test procedure .....	7
7.1 Pre-conditioning .....	7
7.2 Air flow measurement .....	7
7.3 Sampling and monitoring of released nano-objects .....	7
7.3.1 Filter-based sampling methods .....	7
7.3.2 Real-time methods .....	8
8 Determination of qualitative properties of released nano-objects .....	8
8.1 Measurands related to chemical measurement of nano-objects .....	8
8.1.1 General .....	8
8.1.2 TEM/SEM-energy dispersive X-ray spectroscopy (EDX) and wavelength- dispersive X-ray spectroscopy (WDS) .....	9
8.1.3 Electron energy loss spectroscopy (EELS) .....	10
8.1.4 X-ray fluorescence spectroscopy (XRF) .....	10
8.1.5 Auger electron spectroscopy (AES) .....	10
8.1.6 Secondary ion mass spectroscopy (SIMS) .....	11
8.1.7 X-ray photoelectron spectroscopy (XPS) .....	11
8.2 Measurands related to size and shape measurement of nano-objects .....	11
8.2.1 General .....	11
8.2.2 Differential mobility analysing system (DMAS) .....	12
8.2.3 Condensation particle counter (CPC) .....	13
8.2.4 Transmission electron microscopy (TEM) combined with TEM grid samplers .....	13
8.2.5 Scanning electron microscopy (SEM) .....	13
8.2.6 Atomic force microscopy (AFM) .....	14
8.2.7 Single particle inductively coupled plasma-mass spectrometry (SP-ICP-MS) .....	15
8.2.8 Field flow fractionation (FFF) .....	16
9 Reporting .....	17
9.1 General information .....	17
9.2 Mandatory characteristics .....	17
Annex A (informative) Test report format for detection of nano-objects release from mask media ....	18
Bibliography .....	19